

AN79N00 Series

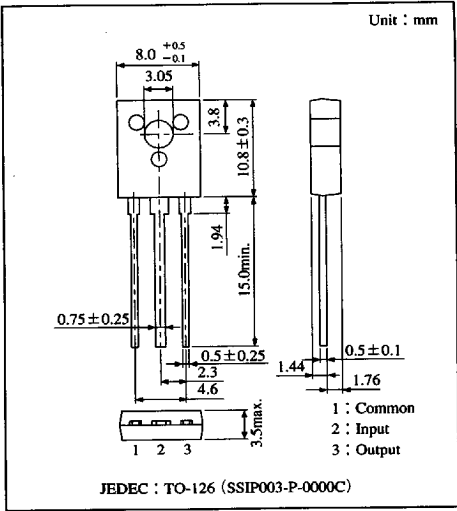
3-pin Negative Output Voltage Regulator (300mA Type)

Overview

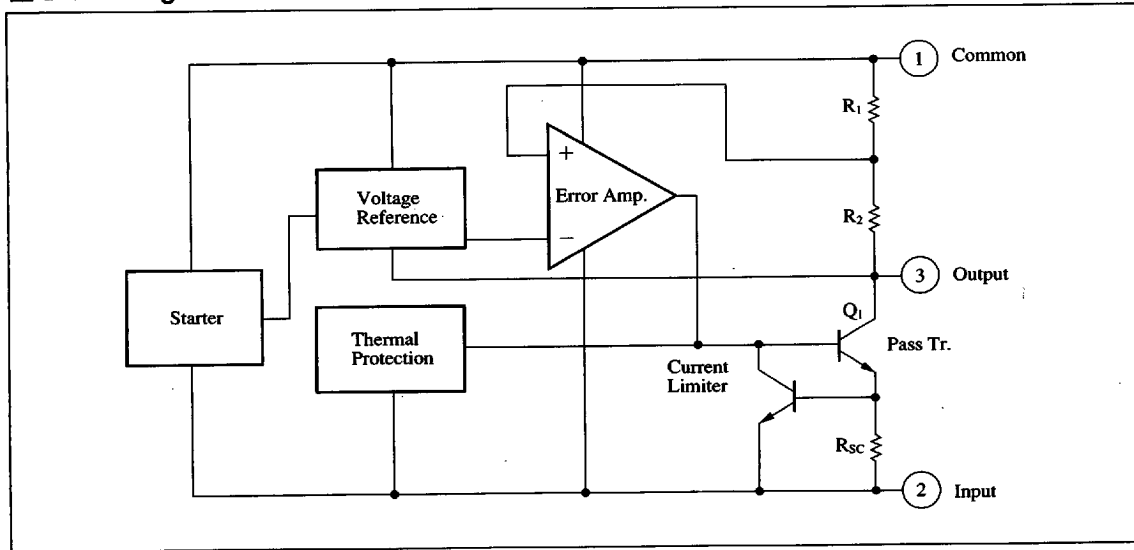
The AN79N00 series is 3-pin fixed negative output voltage regulators. Stabilized fixed output voltage is obtained from unstable DC input voltage without using any external components. 12 types of output voltage are available ; -4V, -5V, -6V, -7V, -8V, -9V, -10V, -12V, -15V, -18V, -20V and -24V. They can be used widely in power circuits with current capacitance up to 300mA.

Features

- No external components
- Output voltage : -4V, -5V, -6V, -7V, -8V, -9V, -10V, -12V, -15V, -18V, -20V, -24V
- Short-circuit current limiting built-in
- Thermal overload protection built-in
- Output transistor safe area compensation



Block Diagram



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■ Absolute Maximum Ratings (Ta=25℃)

Parameter	Symbol	Rating	Unit
Input voltage	Vi	−35 *1	V
		−40 *2	V
Power dissipation	P _D	8 *3	W
Operating ambient temperature	T _{opr}	−20 to +80	℃
Storage temperature	T _{stg}	−55 to +150	℃

*1 AN79N04, AN79N05, AN79N06, AN79N07, AN79N08, AN79N09, AN79N10, AN79N12, AN79N15, AN79N18

*2 AN79N20, AN79N24

*3 Follow the derating curve, When Tj exceeds 150℃, the internal circuit cuts off the output.

■ Electrical Characteristics (Ta=25℃)

• AN79N04 (−4V Type)

Parameter	Symbol	Condition	min	typ	max	Unit
Output voltage	Vo	Tj=25℃	−3.84	−4	−4.16	V
Output voltage tolerance	Vo	Vi=−6 to −25V, Io=5 to 200mA	−3.8	—	−4.2	V
Line regulation	REG _{IN}	Vi=−6 to −25V, Tj=25℃	—	9	40	mV
		Vi=−7 to −17V, Tj=25℃	—	4	20	mV
Load regulation	REG _L	Io=1 to 300mA, Tj=25℃	—	20	80	mV
		Io=5 to 200mA, Tj=25℃	—	10	40	mV
Bias current	I _{Bias}	Tj=25℃	—	3	5	mA
Input bias current fluctuation	ΔI _{Bias (IN)}	Vi=−7 to −25V, Tj=25℃	—	—	0.5	mA
Load bias current fluctuation	ΔI _{Bias (L)}	Io=5 to 200mA, Tj=25℃	—	—	0.1	mA
Output noise voltage	V _{no}	f=10Hz to 100kHz	—	100	—	μV
Ripple rejection ratio	RR	Vi=−7 to −17V, Io=50mA, f=120Hz	60	—	—	dB
Minimum input/output voltage difference	V _{DIF (min.)}	Io=200mA, Tj=25℃	—	1.1	—	V
Output short circuit current	Io (Short)	Vi=−35V, Tj=25℃	—	10	—	mA
Peak output current	Io (Peak)	Tj=25℃	—	500	—	mA
Output voltage temperature coefficient	ΔVo/Ta	Io=5mA	—	−0.4	—	mV/℃

Note 1) The specified condition Tj=25℃ means that the test should be carried out with the test time so short (within 10ms) that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

Note 2) When not specified, Vi=−9V, Io=100mA, Ci=2μF, Co=1μF and Tj=0 to 125℃

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■ Electrical Characteristics (Ta=25°C)

•AN79N05 (−5V Type)

Parameter	Symbol	Condition	min	typ	max	Unit
Output voltage	V_O	$T_j = 25^\circ\text{C}$	−4.8	−5	−5.2	V
Output voltage tolerance	V_O	$V_I = -7$ to -25V , $I_O = 5$ to 200mA	−4.75	—	−5.25	V
Line regulation	REG_{IN}	$V_I = -7$ to -25V , $T_j = 25^\circ\text{C}$	—	10	50	mV
		$V_I = -8$ to -18V , $T_j = 25^\circ\text{C}$	—	5	30	mV
Load regulation	REG_L	$I_O = 1$ to 300mA , $T_j = 25^\circ\text{C}$	—	20	100	mV
		$I_O = 5$ to 200mA , $T_j = 25^\circ\text{C}$	—	10	50	mV
Bias current	I_{Bias}	$T_j = 25^\circ\text{C}$	—	3	5	mA
Input bias current fluctuation	$\Delta I_{\text{Bias (IN)}}$	$V_I = -8$ to -25V , $T_j = 25^\circ\text{C}$	—	—	0.5	mA
Load bias current fluctuation	$\Delta I_{\text{Bias (L)}}$	$I_O = 5$ to 200mA , $T_j = 25^\circ\text{C}$	—	—	0.1	mA
Output noise voltage	V_{no}	$f = 10\text{Hz}$ to 100kHz	—	125	—	μV
Ripple rejection ratio	RR	$V_I = -8$ to -18V , $I_O = 50\text{mA}$, $f = 120\text{Hz}$	60	—	—	dB
Minimum input/output voltage difference	$V_{\text{DIF (min.)}}$	$I_O = 200\text{mA}$, $T_j = 25^\circ\text{C}$	—	1.1	—	V
Output short circuit current	$I_{\text{O (Short)}}$	$V_I = -35\text{V}$, $T_j = 25^\circ\text{C}$	—	10	—	mA
Peak output current	$I_{\text{O (Peak)}}$	$T_j = 25^\circ\text{C}$	—	500	—	mA
Output voltage temperature coefficient	$\Delta V_O/T_a$	$I_O = 5\text{mA}$	—	−0.4	—	mV/°C

Note 1) The specified condition $T_j = 25^\circ\text{C}$ means that the test should be carried out with the test time so short (within 10ms) that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

Note 2) When not specified, $V_I = -10\text{V}$, $I_O = 100\text{mA}$, $C_I = 2\mu\text{F}$, $C_O = 1\mu\text{F}$ and $T_j = 0$ to 125°C

•AN79N06 (−6V Type)

Parameter	Symbol	Condition	min	typ	max	Unit
Output voltage	V_O	$T_j = 25^\circ\text{C}$	−5.75	−6	−6.25	V
Output voltage tolerance	V_O	$V_I = -8$ to -25V , $I_O = 5$ to 200mA	−5.7	—	−6.3	V
Line regulation	REG_{IN}	$V_I = -8$ to -25V , $T_j = 25^\circ\text{C}$	—	11	60	mV
		$V_I = -9$ to -19V , $T_j = 25^\circ\text{C}$	—	6	40	mV
Load regulation	REG_L	$I_O = 1$ to 300mA , $T_j = 25^\circ\text{C}$	—	20	120	mV
		$I_O = 5$ to 200mA , $T_j = 25^\circ\text{C}$	—	10	60	mV
Bias current	I_{Bias}	$T_j = 25^\circ\text{C}$	—	3	5	mA
Input bias current fluctuation	$\Delta I_{\text{Bias (IN)}}$	$V_I = -9$ to -25V , $T_j = 25^\circ\text{C}$	—	—	0.5	mA
Load bias current fluctuation	$\Delta I_{\text{Bias (L)}}$	$I_O = 5$ to 200mA , $T_j = 25^\circ\text{C}$	—	—	0.1	mA
Output noise voltage	V_{no}	$f = 10\text{Hz}$ to 100kHz	—	150	—	μV
Ripple rejection ratio	RR	$V_I = -9$ to -19V , $I_O = 50\text{mA}$, $f = 120\text{Hz}$	60	—	—	dB
Minimum input/output voltage difference	$V_{\text{DIF (min.)}}$	$I_O = 5\text{mA}$, $T_j = 0$ to 125°C	—	1.1	—	V
Output short circuit current	$I_{\text{O (Short)}}$	$V_I = -35\text{V}$, $T_j = 25^\circ\text{C}$	—	10	—	mA
Peak output current	$I_{\text{O (Peak)}}$	$T_j = 25^\circ\text{C}$	—	500	—	mA
Output voltage temperature coefficient	$\Delta V_O/T_a$	$I_O = 200\text{mA}$	—	−0.4	—	mV/°C

Note 1) The specified condition $T_j = 25^\circ\text{C}$ means that the test should be carried out with the test time so short (within 10ms) that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

Note 2) When not specified, $V_I = -11\text{V}$, $I_O = 100\text{mA}$, $C_I = 2\mu\text{F}$, $C_O = 1\mu\text{F}$ and $T_j = 0$ to 125°C

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■ Electrical Characteristics (Ta=25℃)

•AN79N07 (−7V Type)

Parameter	Symbol	Condition	min	typ	max	Unit
Output voltage	V _O	T _J =25℃	−6.7	−7	−7.3	V
Output voltage tolerance	V _O	V _I =−9 to −25V, I _O =5 to 200mA	−6.65	—	−7.35	V
Line regulation	REG _{IN}	V _I =−9 to −25V, T _J =25℃	—	12	70	mV
		V _I =−10 to −20V, T _J =25℃	—	7	35	mV
Load regulation	REG _L	I _O =1 to 300mA, T _J =25℃	—	20	140	mV
		I _O =5 to 200mA, T _J =25℃	—	10	70	mV
Bias current	I _{Bias}	T _J =25℃	—	3	5	mA
Input bias current fluctuation	ΔI _{Bias (IN)}	V _I =−10 to −25V, T _J =25℃	—	—	0.5	mA
Load bias current fluctuation	ΔI _{Bias (L)}	I _O =5 to 200mA, T _J =25℃	—	—	0.1	mA
Output noise voltage	V _{no}	f=10Hz to 100kHz	—	175	—	μV
Ripple rejection ratio	RR	V _I =−10 to −20V, I _O =50mA, f=120Hz	59	—	—	dB
Minimum input/output voltage difference	V _{DIF (min.)}	I _O =200mA, T _J =25℃	—	1.1	—	V
Output short circuit current	I _{O (Short)}	V _I =−35V, T _J =25℃	—	10	—	mA
Peak output current	I _{O (Peak)}	T _J =25℃	—	500	—	mA
Output voltage temperature coefficient	ΔV _O /Ta	I _O =5mA	—	−0.5	—	mV/℃

Note 1) The specified condition T_J=25℃ means that the test should be carried out with the test time so short (within 10ms) that the drift in characteristic value due to the rise in chip junction temperature can be ignored.
Note 2) When not specified, V_I=−12V, I_O=100mA, C_I=2 μF, C_O=1 μF and T_J=0 to 125℃

• AN79N08 (−8V Type)

Parameter	Symbol	Condition	min	typ	max	Unit
Output voltage	V _O	T _J =25℃	−7.7	−8	−8.3	V
Output voltage tolerance	V _O	V _I =−10.5 to −25V, I _O =5 to 200mA	−7.6	—	−8.4	V
Line regulation	REG _{IN}	V _I =−10.5 to −25V, T _J =25℃	—	13	80	mV
		V _I =−11 to −21V, T _J =25℃	—	8	40	mV
Load regulation	REG _L	I _O =1 to 300mA, T _J =25℃	—	25	160	mV
		I _O =5 to 200mA, T _J =25℃	—	10	80	mV
Bias current	I _{Bias}	T _J =25℃	—	3	5	mA
Input bias current fluctuation	ΔI _{Bias (IN)}	V _I =−10.5 to −25V, T _J =25℃	—	—	0.5	mA
Load bias current fluctuation	ΔI _{Bias (L)}	I _O =5 to 200mA, T _J =25℃	—	—	0.1	mA
Output noise voltage	V _{no}	f=10Hz to 100kHz	—	200	—	μV
Ripple rejection ratio	RR	V _I =−11.5 to −21.5V, I _O =50mA, f=120Hz	59	—	—	dB
Minimum input/output voltage difference	V _{DIF (min.)}	I _O =200mA, T _J =25℃	—	1.1	—	V
Output short circuit current	I _{O (Short)}	V _I =−35V, T _J =25℃	—	10	—	mA
Peak output current	I _{O (Peak)}	T _J =25℃	—	500	—	mA
Output voltage temperature coefficient	ΔV _O /Ta	I _O =5mA	—	−0.6	—	mV/℃

Note 1) The specified condition T_J=25℃ means that the test should be carried out with the test time so short (within 10ms) that the drift in characteristic value due to the rise in chip junction temperature can be ignored.
Note 2) When not specified, V_I=−14V, I_O=100mA, C_I=2 μF, C_O=1 μF and T_J=0 to 125℃

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■ Electrical Characteristics (Ta=25℃)

• AN79N09 (−9V Type)

Parameter	Symbol	Condition	min	typ	max	Unit
Output voltage	V_O	$T_j=25^{\circ}\text{C}$	−8.65	−9	−9.35	V
Output voltage tolerance	V_O	$V_I=-11.5\text{ to }-26\text{V}$, $I_O=5\text{ to }200\text{mA}$	−8.55	—	−9.45	V
Line regulation	REG_{IN}	$V_I=-11.5\text{ to }-26\text{V}$, $T_j=25^{\circ}\text{C}$	—	14	80	mV
		$V_I=-12\text{ to }-22\text{V}$, $T_j=25^{\circ}\text{C}$	—	9	50	mV
Load regulation	REG_L	$I_O=1\text{ to }300\text{mA}$, $T_j=25^{\circ}\text{C}$	—	25	180	mV
		$I_O=5\text{ to }200\text{mA}$, $T_j=25^{\circ}\text{C}$	—	10	90	mV
Bias current	I_{Bias}	$T_j=25^{\circ}\text{C}$	—	3	5	mA
Input bias current fluctuation	$\Delta I_{\text{Bias (IN)}}$	$V_I=-11.5\text{ to }-26\text{V}$, $T_j=25^{\circ}\text{C}$	—	—	0.5	mA
Load bias current fluctuation	$\Delta I_{\text{Bias (L)}}$	$I_O=5\text{ to }200\text{mA}$, $T_j=25^{\circ}\text{C}$	—	—	0.1	mA
Output noise voltage	V_{no}	$f=10\text{Hz to }100\text{kHz}$	—	225	—	μV
Ripple rejection ratio	RR	$V_I=-12\text{ to }-22\text{V}$, $I_O=50\text{mA}$, $f=120\text{Hz}$	58	—	—	dB
Minimum input/output voltage difference	$V_{\text{DIF(min.)}}$	$I_O=200\text{mA}$, $T_j=25^{\circ}\text{C}$	—	1.1	—	V
Output short circuit current	$I_{\text{O(Short)}}$	$V_I=-35\text{V}$, $T_j=25^{\circ}\text{C}$	—	10	—	mA
Peak output current	$I_{\text{O(Peak)}}$	$T_j=25^{\circ}\text{C}$	—	500	—	mA
Output voltage temperature coefficient	$\Delta V_O/T_a$	$I_O=5\text{mA}$	—	−0.6	—	mV/℃

Note 1) The specified condition $T_j=25^{\circ}\text{C}$ means that the test should be carried out with the test time so short (within 10ms) that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

Note 2) When not specified, $V_I=-15\text{V}$, $I_O=100\text{mA}$, $C_I=2\mu\text{F}$, $C_O=1\mu\text{F}$ and $T_j=0\text{ to }125^{\circ}\text{C}$

• AN79N10 (−10V Type)

Parameter	Symbol	Condition	min	typ	max	Unit
Output voltage	V_O	$T_j=25^{\circ}\text{C}$	−9.6	−10	−10.4	V
Output voltage tolerance	V_O	$V_I=-12.5\text{ to }-27\text{V}$, $I_O=5\text{ to }200\text{mA}$	−9.5	—	−10.5	V
Line regulation	REG_{IN}	$V_I=-12.5\text{ to }-27\text{V}$, $T_j=25^{\circ}\text{C}$	—	15	80	mV
		$V_I=-13\text{ to }-23\text{V}$, $T_j=25^{\circ}\text{C}$	—	10	50	mV
Load regulation	REG_L	$I_O=1\text{ to }300\text{mA}$, $T_j=25^{\circ}\text{C}$	—	25	200	mV
		$I_O=5\text{ to }200\text{mA}$, $T_j=25^{\circ}\text{C}$	—	10	100	mV
Bias current	I_{Bias}	$T_j=25^{\circ}\text{C}$	—	3.0	5	mA
Input bias current fluctuation	$\Delta I_{\text{Bias (IN)}}$	$V_I=-12.5\text{ to }-27\text{V}$, $T_j=25^{\circ}\text{C}$	—	—	0.5	mA
Load bias current fluctuation	$\Delta I_{\text{Bias (L)}}$	$I_O=5\text{ to }200\text{mA}$, $T_j=25^{\circ}\text{C}$	—	—	0.1	mA
Output noise voltage	V_{no}	$f=10\text{Hz to }100\text{kHz}$	—	250	—	μV
Ripple rejection ratio	RR	$V_I=-13\text{ to }-23\text{V}$, $I_O=50\text{mA}$, $f=120\text{Hz}$	58	—	—	dB
Minimum input/output voltage difference	$V_{\text{DIF(min.)}}$	$I_O=200\text{mA}$, $T_j=25^{\circ}\text{C}$	—	1.1	—	V
Output short circuit current	$I_{\text{O(Short)}}$	$V_I=-35\text{V}$, $T_j=25^{\circ}\text{C}$	—	10	—	mA
Peak output current	$I_{\text{O(Peak)}}$	$T_j=25^{\circ}\text{C}$	—	500	—	mA
Output voltage temperature coefficient	$\Delta V_O/T_a$	$I_O=5\text{mA}$	—	−0.7	—	mV/℃

Note 1) The specified condition $T_j=25^{\circ}\text{C}$ means that the test should be carried out with the test time so short (within 10ms) that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

Note 2) When not specified, $V_I=-16\text{V}$, $I_O=100\text{mA}$, $C_I=2\mu\text{F}$, $C_O=1\mu\text{F}$ and $T_j=0\text{ to }125^{\circ}\text{C}$

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■ Electrical Characteristics (Ta=25℃)

• AN79N12 (−12V Type)

Parameter	Symbol	Condition	min	typ	max	Unit
Output voltage	Vo	Tj=25℃	−11.5	−12	−12.5	V
Output voltage tolerance	Vo	V1=−14.5 to −30V, Io=5 to 200mA	−11.4	—	−12.6	V
Line regulation	REGIN	V1=−14.5 to −30V, Tj=25℃	—	15	80	mV
		V1=−15 to −25V, Tj=25℃	—	10	50	mV
Load regulation	REGL	Io=1 to 300mA, Tj=25℃	—	25	240	mV
		Io=5 to 200mA, Tj=25℃	—	10	120	mV
Bias current	IBias	Tj=25℃	—	3	5	mA
Input bias current fluctuation	ΔIBias(IN)	V1=−14.5 to −30V, Tj=25℃	—	—	0.5	mA
Load bias current fluctuation	ΔIBias(L)	Io=5 to 200mA, Tj=25℃	—	—	0.1	mA
Output noise voltage	Vno	f=10Hz to 100kHz	—	300	—	μV
Ripple rejection ratio	RR	V1=−15 to −25V, Io=50mA, f=120Hz	57	—	—	dB
Minimum input/output voltage difference	VDIF(min.)	Io=200mA, Tj=25℃	—	1.1	—	V
Output short circuit current	IO(Short)	V1=−35V, Tj=25℃	—	10	—	mA
Peak output current	IO(Peak)	Tj=25℃	—	500	—	mA
Output voltage temperature coefficient	ΔVo/Ta	Io=5mA	—	−0.8	—	mV/℃

Note 1) The specified condition Tj=25℃ means that the test should be carried out with the test time so short (within 10ms) that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

Note 2) When not specified, V1=−19V, Io=100mA, C1=2μF, Co=1μF and Tj=0 to 125℃

• AN79N15 (−15V Type)

Parameter	Symbol	Condition	min	typ	max	Unit
Output voltage	Vo	Tj=25℃	−14.4	−15	−15.6	V
Output voltage tolerance	Vo	V1=−17.5 to −30V, Io=5 to 200mA	−14.25	—	−15.75	V
Line regulation	REGIN	V1=−17.5 to −30V, Tj=25℃	—	16	80	mV
		V1=−18 to −28V, Tj=25℃	—	11	50	mV
Load regulation	REGL	Io=1 to 300mA, Tj=25℃	—	25	240	mV
		Io=5 to 200mA, Tj=25℃	—	10	120	mV
Bias current	IBias	Tj=25℃	—	3	5	mA
Input bias current fluctuation	ΔIBias(IN)	V1=−17.5 to −30V, Tj=25℃	—	—	0.5	mA
Load bias current fluctuation	ΔIBias(L)	Io=5 to 200mA, Tj=25℃	—	—	0.1	mA
Output noise voltage	Vno	f=10Hz to 100kHz	—	375	—	μV
Ripple rejection ratio	RR	V1=−18 to −28V, Io=50mA, f=120Hz	56	—	—	dB
Minimum input/output voltage difference	VDIF(min.)	Io=200mA, Tj=25℃	—	1.1	—	V
Output short circuit current	IO(Short)	V1=−35V, Tj=25℃	—	10	—	mA
Peak output current	IO(Peak)	Tj=25℃	—	500	—	mA
Output voltage temperature coefficient	ΔVo/Ta	Io=5mA	—	−0.9	—	mV/℃

Note 1) The specified condition Tj=25℃ means that the test should be carried out with the test time so short (within 10ms) that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

Note 2) When not specified, V1=−23V, Io=100mA, C1=2μF, Co=1μF and Tj=0 to 125℃

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■ Electrical Characteristics (Ta=25°C)

• AN79N18 (−18V Type)

Parameter	Symbol	Condition	min	typ	max	Unit
Output voltage	V_O	$T_J=25^{\circ}\text{C}$	−17.3	−18	−18.7	V
Output voltage tolerance	V_O	$V_I=-21\text{ to }-33\text{V}, I_O=5\text{ to }200\text{mA}$	−17.1	—	−18.9	V
Line regulation	REG_{IN}	$V_I=-21\text{ to }-33\text{V}, T_J=25^{\circ}\text{C}$	—	18	80	mV
		$V_I=-22\text{ to }-32\text{V}, T_J=25^{\circ}\text{C}$	—	13	50	mV
Load regulation	REG_L	$I_O=1\text{ to }300\text{mA}, T_J=25^{\circ}\text{C}$	—	30	300	mV
		$I_O=5\text{ to }200\text{mA}, T_J=25^{\circ}\text{C}$	—	10	150	mV
Bias current	I_{Bias}	$T_J=25^{\circ}\text{C}$	—	3	5	mA
Input bias current fluctuation	$\Delta I_{\text{Bias (IN)}}$	$V_I=-21\text{ to }-33\text{V}, T_J=25^{\circ}\text{C}$	—	—	0.5	mA
Load bias current fluctuation	$\Delta I_{\text{Bias (L)}}$	$I_O=5\text{ to }200\text{mA}, T_J=25^{\circ}\text{C}$	—	—	0.1	mA
Output noise voltage	V_{no}	$f=10\text{Hz to }100\text{kHz}$	—	450	—	μV
Ripple rejection ratio	RR	$V_I=-22\text{ to }-32\text{V}, I_O=50\text{mA}, f=120\text{Hz}$	55	—	—	dB
Minimum input/output voltage difference	$V_{\text{DIF (min.)}}$	$I_O=200\text{mA}, T_J=25^{\circ}\text{C}$	—	1.1	—	V
Output short circuit current	$I_{\text{O (Short)}}$	$V_I=-35\text{V}, T_J=25^{\circ}\text{C}$	—	10	—	mA
Peak output current	$I_{\text{O (Peak)}}$	$T_J=25^{\circ}\text{C}$	—	500	—	mA
Output voltage temperature coefficient	$\Delta V_O/T_a$	$I_O=5\text{mA}$	—	−1	—	mV/°C

Note 1) The specified condition $T_J=25^{\circ}\text{C}$ means that the test should be carried out with the test time so short (within 10ms) that the drift in characteristic value due to the rise in chip junction temperature can be ignored.
Note 2) When not specified, $V_I=-27\text{V}$, $I_O=100\text{mA}$, $C_I=2\mu\text{F}$, $C_O=1\mu\text{F}$ and $T_J=0\text{ to }125^{\circ}\text{C}$

• AN79N20 (−20V Type)

Parameter	Symbol	Condition	min	typ	max	Unit
Output voltage	V_O	$T_J=25^{\circ}\text{C}$	−19.2	−20	−20.8	V
Output voltage tolerance	V_O	$V_I=-23\text{ to }-35\text{V}, I_O=5\text{ to }200\text{mA}$	−19	—	−21	V
Line regulation	REG_{IN}	$V_I=-23\text{ to }-35\text{V}, T_J=25^{\circ}\text{C}$	—	19	80	mV
		$V_I=-24\text{ to }-34\text{V}, T_J=25^{\circ}\text{C}$	—	14	70	mV
Load regulation	REG_L	$I_O=1\text{ to }300\text{mA}, T_J=25^{\circ}\text{C}$	—	30	300	mV
		$I_O=5\text{ to }200\text{mA}, T_J=25^{\circ}\text{C}$	—	10	150	mV
Bias current	I_{Bias}	$T_J=25^{\circ}\text{C}$	—	3	5	mA
Input bias current fluctuation	$\Delta I_{\text{Bias (IN)}}$	$V_I=-23\text{ to }-35\text{V}, T_J=25^{\circ}\text{C}$	—	—	0.5	mA
Load bias current fluctuation	$\Delta I_{\text{Bias (L)}}$	$I_O=5\text{ to }200\text{mA}, T_J=25^{\circ}\text{C}$	—	—	0.1	mA
Output noise voltage	V_{no}	$f=10\text{Hz to }100\text{kHz}$	—	500	—	μV
Ripple rejection ratio	RR	$V_I=-24\text{ to }-34\text{V}, I_O=50\text{mA}, f=120\text{Hz}$	54	—	—	dB
Minimum input/output voltage difference	$V_{\text{DIF (min.)}}$	$I_O=200\text{mA}, T_J=25^{\circ}\text{C}$	—	1.1	—	V
Output short circuit current	$I_{\text{O (Short)}}$	$V_I=-35\text{V}, T_J=25^{\circ}\text{C}$	—	10	—	mA
Peak output current	$I_{\text{O (Peak)}}$	$T_J=25^{\circ}\text{C}$	—	500	—	mA
Output voltage temperature coefficient	$\Delta V_O/T_a$	$I_O=5\text{mA}$	—	−1	—	mV/°C

Note 1) The specified condition $T_J=25^{\circ}\text{C}$ means that the test should be carried out with the test time so short (within 10ms) that the drift in characteristic value due to the rise in chip junction temperature can be ignored.
Note 2) When not specified, $V_I=-29\text{V}$, $I_O=100\text{mA}$, $C_I=2\mu\text{F}$, $C_O=1\mu\text{F}$ and $T_J=0\text{ to }125^{\circ}\text{C}$

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■ Electrical Characteristics (Ta=25℃)

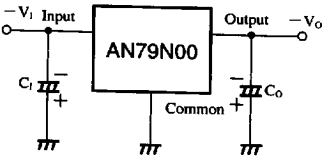
• AN79N24 (−24V Type)

Parameter	Symbol	Condition	min	typ	max	Unit
Output voltage	VO	Tj=25℃	−23	−24	−25	V
Output voltage tolerance	VO	V1=−27 to −38V, Io=5 to 200mA	−22.8	—	−25.2	V
Line regulation	REGIN	V1=−27 to −38V, Tj=25℃	—	20	80	mV
		V1=−27 to −37V, Tj=25℃	—	15	70	mV
Load regulation	REGL	Io=1 to 300mA, Tj=25℃	—	30	300	mV
		Io=5 to 200mA, Tj=25℃	—	10	150	mV
Bias current	IBias	Tj=25℃	—	3	5	mA
Input bias current fluctuation	ΔIBias(IN)	V1=−27 to −38V, Tj=25℃	—	—	0.5	mA
Load bias current fluctuation	ΔIBias(L)	Io=5 to 200mA, Tj=25℃	—	—	0.1	mA
Output noise voltage	Vno	f=10Hz to 100kHz	—	600	—	μV
Ripple rejection ratio	RR	V1=−28 to −38V, Io=50mA, f=120Hz	54	—	—	dB
Minimum input/output voltage difference	VDIF(min.)	Io=200mA, Tj=25℃	—	1.1	—	V
Output short circuit current	IO(Short)	V1=−35V, Tj=25℃	—	10	—	mA
Peak output current	IO(Peak)	Tj=25℃	—	500	—	mA
Output voltage temperature coefficient	ΔVO/Ta	Io=5mA	—	−1	—	mV/℃

Note 1) The specified condition Tj=25℃ means that the test should be carried out with the test time so short (within 10ms) that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

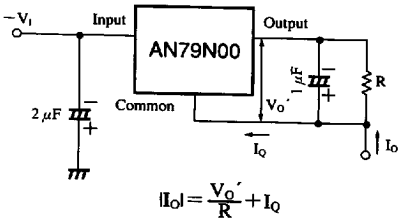
Note 2) When not specified, V1=−33V, Io=100mA, C1=2 μF, C0=1 μF and Tj=0 to 125℃

■ Basic Regulator Circuit



C1 is connected when the input line is long. 2 μF
C0 improves the transient response. 1 μF

■ Application Circuit



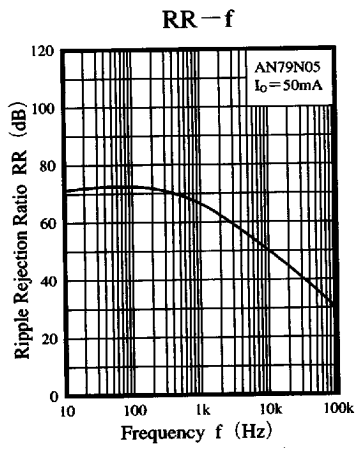
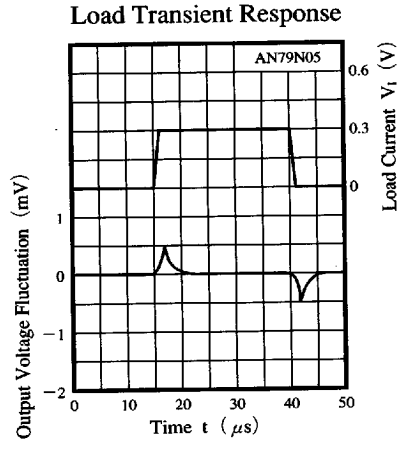
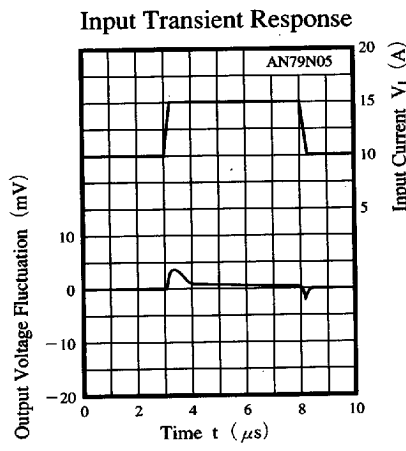
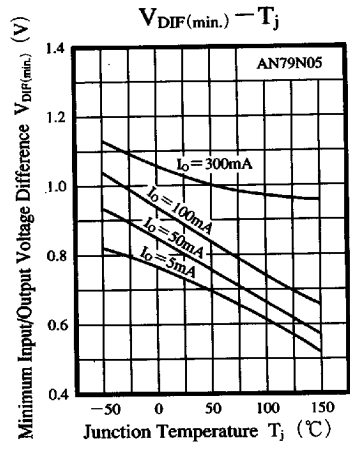
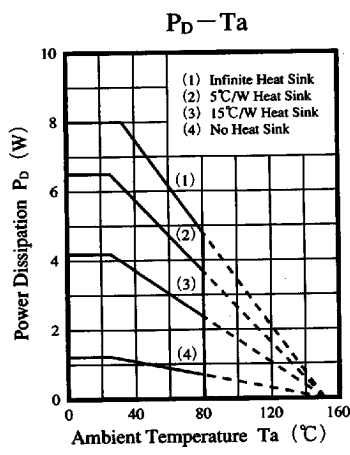
$$|I_{O1}| = \frac{V_{O'}}{R} + I_O$$

Voltage
Regu-
lators

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■ Characteristics Curve



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